REMARKS

Applicant requests entry of the proposed changes submitted herewith to correct minor deficiencies to the specification. No new matter has been added. Early consideration and quick passage to issue is earnestly solicited.

If there are any fees due in connection with the filing of this response, please charge such fees to our Deposit Account No. 17-0026. If a fee is required for an extension of time under 37 C.F.R. 1.136 not accounted for, such an extension is requested and the fee should also be charged to our Deposit Account. A duplicate copy of this page is enclosed.

Respectfully submitted,

Dated: November 26, 2003

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COPY

CALIBRATING AN INTEGRATED CIRCUIT TO AN ELECTRONIC DEVICE

CROSS REFERENCE TO RELATED APPLICATIONS

[0001] This application is related to and claims the benefit of the filing date of U.S. provisional application (Attorney docket no. 50278-093), by Jagrut Patel, et. al., filed on November 24, 2003, entitled "Calibrating an Integrated Circuit to an Electronic Device."

BACKGROUND

Field

[0002] The present disclosure relates to systems and techniques for calibrating an integrated circuit to an electronic device.

Background

[0003] Integrated circuits have revolutionized the electronics industry by enabling new applications which were not possible with discrete devices. Integration allows complex circuits consisting of millions of electronic components to be packaged into a single chip of semiconductor material. In addition, integration offers the advantages of fabricating hundreds of chips on a single silicon wafer, which greatly reduces the cost and increases the reliability of each of the finished circuits.

[0004] Integrated circuits are widely used today in electronic devices to implement sophisticated circuitry such as general purpose and specific application processors. A controller integrated onto the chip may be used to interface the various processors with off-chip components, such as external memory and the like. Clocks generated by the controller may be used to access these off-chip components. These clocks should operate at a specific nominal speed, within a certain allowed tolerance, to ensure that the controller can communicate with the off-chip components under worst case temperature and voltage conditions.

[0005] Due to processes inherent in the silicon wafer fabrication process, a set of chips generated from a single wafer may fall into a range of different process speed ratings. Depending on the application, some manufacturers are forced to discard slow

Copy of specification previously filed for reference.